Search Notes		
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	41:0 01:61 11001 61:18 16:11 00:10 1101 180	ı

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/615,902	IANCU ET AL.	
Examiner	Art Unit	
Leila Malek	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	316	6/20/2006	L.M
455	456.1	6/20/2006	L.M
370	329	6/20/2006	L.M
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEAF)
	DATE	EXMR
EAST	6/20/2006	L.M
IEEE	6/20/2006	L.M
GOOGLE	6/20/2006	L.M
Consulted M. Ghayour	6/20/2006	L.M